

Search Notes

Application/Control No.

10/086,262

Examiner

Steven HD Nguyen

Applicant(s)/Patent under
Reexamination

CHANG ET AL.

Art Unit

2665

SEARCHED

Class	Subclass	Date	Examiner
370	351-356, 401	1/31/2006	ST
379	265.02		
	88.17		
	900		
	142.07		
	210.01		
	225, 231		
	265.09		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR